

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/721,549	NAKAMURA ET AL.
	Examiner	Art Unit
	Hien N. Nguyen	2824

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
365	171	2/22/2005	HN
	158		
	173		